

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination SOMERVILLE, DECLAN	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-1,167,746 A	01-1916	Funsten	52/574
*	B	US-2,065,493 A	12-1936	GREULICH GERALD G	52/731.1
*	C	US-2,082,792 A	06-1937	DEAN ALBERT G	52/737.6
*	D	US-2,125,691 A	08-1938	RAGSDALE EARL J W; et. al.	52/731.2
*	E	US-2,125,692 A	08-1938	RAGSDALE EARL J W; et. al.	52/731.2
*	F	US-2,125,690 A	08-1938	RAGSDALE EARL J W; et. al.	52/731.2
*	G	US-2,508,032 A	05-1950	KENNEDY BENJAMIN H	52/731.7
*	H	US-3,698,149 A	10-1972	Baker et al.	52/732.2
*	I	US-3,757,485 A	09-1973	Vincens, Rene	52/731.2
*	J	US-3,877,193 A	04-1975	Hall, Raymond L.	52/665
*	K	US-3,977,149 A	08-1976	Haynes et al.	52/732.1
*	L	US-D242,625 S	12-1976	Schmidt, Dietrich F.	D25/121
*	M	US-D242,626 S	12-1976	Scrivener, Ian	D25/123

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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	T					

NON-PATENT DOCUMENTS

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	U	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-D242,627 S	12-1976	Scrivener, Ian	D25/123
*	B	US-D242,628 S	12-1976	Scrivener, Ian	D25/123
*	C	US-4,192,119 A	03-1980	Murphy, Wesley T.	52/731.3
*	D	US-4,704,832 A	11-1987	Vassiliadis, Theodor	52/279
*	E	US-4,987,717 A	01-1991	Dameron, Jr., Joseph T.	52/732.1
*	F	US-5,398,909 A	03-1995	Sandwith, Stanley R.	249/207
*	G	US-5,464,302 A	11-1995	Menchetti, Robert J.	403/335
*	H	US-5,545,488 A	08-1996	Burke, Ralph C.	428/586
*	I	US-5,555,695 A	09-1996	Patsy, Jr., Glorio J.	52/730.4
*	J	US-5,553,437 A	09-1996	Navon, Ram	52/729.1
*	K	US-D378,424 S	03-1997	Leonelli, Louie	D25/122
*	L	US-5,806,268 A	09-1998	Koller, Ernst	52/653.1
*	M	US-5,881,508 A	03-1999	Irvine et al.	52/177

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,904,022 A	05-1999	Zadok, Yigal	52/650.1
*	B	US-6,185,878 B1	02-2001	Bullard et al.	52/79.5
*	C	US-6,446,414 B1	09-2002	Bullard et al.	52/764
*	D	US-2002/0148191 A1	10-2002	Hynes, Thomas C.	52/729.1
*	E	US-6,519,911 B1	02-2003	Sawada, Taiichi	52/730.4
*	F	US-6,658,808 B1	12-2003	Doherty et al.	52/580
*	G	US-6,915,616 B2	07-2005	Fontana et al.	52/731.2
*	H	US-2006/0179789 A1	08-2006	Nicoletti, Bruno	052/741.15
*	I	US-D567,397 S	04-2008	Terada et al.	D25/126
J	US-				
K	US-				
L	US-				
M	US-				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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